

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Applicants:** A. Bhavnagarwala et al.

**Examiner:** West, Jeffrey R.

**Serial No.:** 10/643,193

**Group:** Art Unit 2857

**Filed:** August 18, 2003

**Docket:** YOR920030289US1 (8728-635)

**For:**                   **CIRCUITS AND METHODS FOR CHARACTERIZING  
RANDOM VARIATIONS IN DEVICE CHARACTERISTICS  
IN SEMICONDUCTOR INTEGRATED CIRCUITS**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313

**AMENDMENT**

This is a response to the Office Action mailed on July 26, 2006. Please amend the application as follows: